

Abstract of disclosure

A test method and an arrangement for testing an RF circuit of a wireless device are provided. The test arrangement includes providing means connected to the RF circuit, the providing means for providing the RF circuit to be tested
5 with an input test signal, thus generating an RF output test signal characterizing the response of the RF circuit, and down-converting means connected to the RF circuit and integrated at least partially into the RF circuit, the down-converting means for down-converting the RF output test signal to a BB frequency, thus generating a BB output test signal. The invention provides access
10 to the RF circuit by using relatively simple test instrumentation operating at a base band frequency.